

Notice of References Cited	Application/Control No. 10/625,567	Applicant(s)/Patent Under Reexamination FUNAKOSHI ET AL.	
	Examiner Nhan T. Tran	Art Unit 2622	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,831,686	12-2004	Koren et al.	348/241
*	B	US-6,433,822	08-2002	Clark et al.	348/241
*	C	US-6,844,896	01-2005	Henderson et al.	348/248
*	D	US-2003/0202111	10-2003	Park, Jaejin	348/280
*	E	US-2003/0016294	01-2003	Chiu, Sean	348/241
*	F	US-6,201,582	03-2001	Hentschel, Christian	348/607
*	G	US-6,847,176	01-2005	Kim, Kyoung-hwan	348/E5.077
*	H	US-6,747,264	06-2004	Miida, Takashi	348/300
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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